

TEM • CROSS SECTION POLISHER • MICROPROBE • SEM • ANALYTICAL MICROSCOPES

JEOL *ink*

JEOL USA News - Imaging & Microanalysis and More

Issue: #59

November 2015



Upcoming Events

2015 Schedule of Events

To request a demo please contact your local sales representative.

2015 Training Schedule at
JEOL USA

Hooke College of Applied Sciences SEM/TEM Training

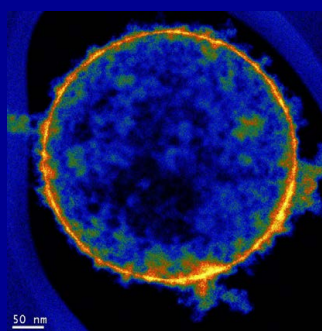


News Corner



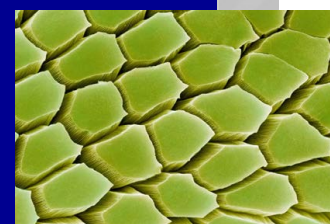
"Ideal for Space" Beryllium used to produce mirrors for the James Webb Space Telescope (SEM images shown) in September AM&P article. (Click image)

Congratulations to JEOL 2015 Monthly Image Contest Winners



OCTOBER

"Nano Sun" 500 nanometer silicate nanoshell particle. Prof. Moon Kim's group, University of Texas at Dallas.

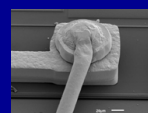


SEPTEMBER

"Sticky" Finger tips of Eleutherodactylus (Coqui frog). Jose R. Rodriguez, University of Puerto Rico, Mayaguez Campus

Just 2 months to go before the end of the 2015 contest! We will choose 2 more monthly winners and 2 Grand Prize winners in the SEM and TEM category.

[>>>Visit the Image Contest gallery and guidelines here<<<](#)



Webinar: Explore the Smaller World of the Automotive Industry with Benchtop SEM

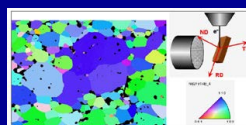
Join us **November 12** for an exclusive webinar presented by Nikon and JEOL on:

- The basics of SEM for inspection, QC, metallography, and FA
- Use of SEM for R&D
- Advantages of NeoScope JCM-6000 Plus benchtop SEM

More information [click here](#).

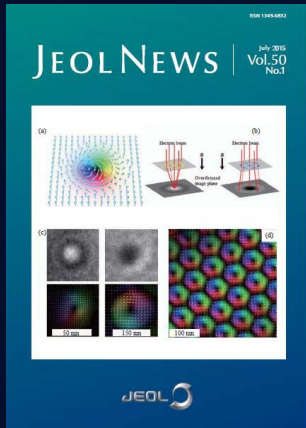
[>>>Register Now<<<](#)

EBSD Characterization with FE SEM

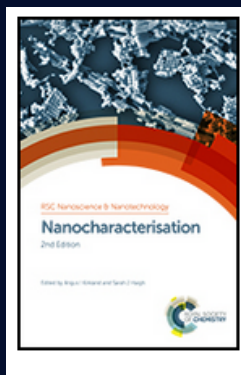


Electron Backscatter Diffraction (EBSD) is a powerful technique capable of characterizing extremely fine grained microstructures in a Scanning Electron Microscope (SEM). Electron Backscatter Patterns (EBSPs) are generated near the sample surface, typically from a depth in the range 10 - 50nm. In order to achieve effective analysis it is imperative to combine high beam current with small probe size to achieve high spatial

JEOL News 2015
Request a copy.



Click image for Table of Contents



Nanocharacterisation (Ed. 2)

Featuring chapter on Scanning Electron and Ion Microscopy of Nanostructured Materials - Authors include Dr. Natasha Erdman of JEOL USA.



Quick Links

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- or -

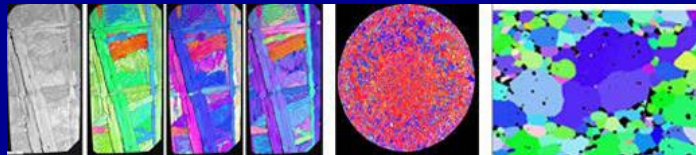
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resolution in a time efficient manner.

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Workshop: New Analytical Capabilities with EBSD, EDS and FE SEM

Hosted by JEOL and Bruker **December 2-3, 2015** at JEOL USA

Day One: lectures and demonstrations

- [FEG SEM Ultra Low kV Imaging and Microanalysis Some Amazing Data \(Doing the Almost Impossible\) and Some Words of Caution](#)
- [Transmission Kikuchi Diffraction \(TKD\) in SEM Using On-Axis Detector](#)

Day Two: One-on-one demonstrations Pre-scheduled time slots.

[>>>Register Now<<<](#)

New Versatile High Throughput SEM



The new IT100 is a simple-to-use versatile, research-grade SEM with a compact ergonomic design. It features high resolution imaging in HV/LV/SE/BSE, and chemical analysis with integrated EDS. Check out the the latest in SEM technology based on more than 50 years of microscopy expertise at JEOL.

Learn more about the [IT100 InTouchScope SEM](#) [here](#).



Universidad de la República - Uruguay

JEOL Brasil Website
 JEOL de Mexico
 Website



Since 2000, scientists from the Universidad de la República in Uruguay have been revealing remarkable details about anatomy that has had an impact on research and veterinary medicine worldwide, with numerous publications to their credit.

Currently, Dr. Silvia Villar Arias (Faculty of Science, UdelaR) and Dr. William Perez (Professor of Anatomy at the Veterinary Faculty) are developing comparative anatomy studies, focusing on the native fauna of Uruguay.

[More>>>](#)



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Archived Issues

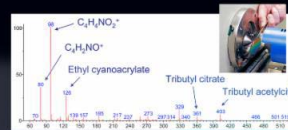
Chemistry Corner

Mass Spectrometry for Failure Analysis?

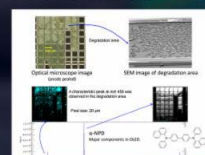
Check out our [applications notes and mass spec solutions](#) for Direct Analysis in Real Time (DART), open air, gas chromatography, and MALDI imaging.

For news and applications data from JEOL mass spectrometers and NMR systems, [click to read Mass Media Newsletter.](#)

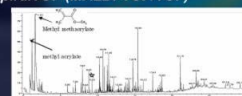
Mass Spectrometry for Failure Analysis



Direct analysis of adhesives and polymers AccuTOF-DART (ambient ionization)



MS imaging of contamination on OLED panel SpiraiTOF (MALDI-TOF/TOF)



Pyrolysis GC/HRMS analysis of a resin AccuTOF-GCX (GC/TOFMS)



WHEN FA = FAST ANSWERS FOR FAILURE ANALYSIS

Look to JEOL for reliable imaging and analytical tools designed for both routine and exciting failure analysis. JEOL SEMs, TEMs, and sample preparation instruments are versatile, easy to use, and an uncompromising choice when it comes to imaging speed, area, speed, and bottom line. JEOL stands by its service, technical, and application support.

Fast Answers with High Resolution Imaging and Analysis

- All-in-One Analytical Field Emission SEM
- Compact, High Throughput SEM
- Cross-Section Puller with Specimen Coating/Air Injection
- Atomic resolution Cs Corrected TEM with Cold FEG
- Large-Angle SPC-ISE, Automated S-TEM
- Benchtop ED-XRF Elemental Analysis

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